



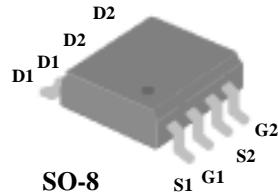
Advanced Power Electronics Corp.

**N AND P-CHANNEL ENHANCEMENT
MODE POWER MOSFET**

▼ Simple Drive Requirement

▼ Low On-resistance

▼ Fast Switching Performance

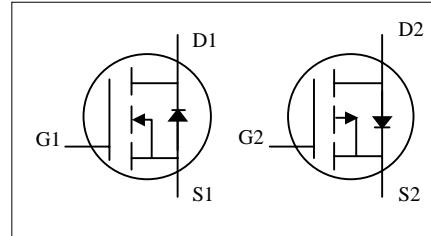


Description

The Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

N-CH	BV_{DSS}	60V
	$R_{DS(ON)}$	36mΩ
	I_D	6A
P-CH	BV_{DSS}	-60V
	$R_{DS(ON)}$	72mΩ
	I_D	-4.2A



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-channel	P-channel	
V_{DS}	Drain-Source Voltage	60	-60	V
V_{GS}	Gate-Source Voltage	± 20	± 20	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	6	-4.2	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	4.7	-3.3	A
I_{DM}	Pulsed Drain Current ¹	30	-30	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2.0		W
	Linear Derating Factor	0.016		W/°C
T_{STG}	Storage Temperature Range	-55 to 150		°C
T_J	Operating Junction Temperature Range	-55 to 150		°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-a}	Thermal Resistance Junction-ambient ³	Max.	62.5



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N-CH Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=1\text{mA}$	-	0.04	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=5\text{A}$	-	-	36	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=3\text{A}$	-	-	42	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=5\text{A}$	-	8	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
	Drain-Source Leakage Current ($T_j=70^\circ\text{C}$)	$V_{\text{DS}}=48\text{V}, V_{\text{GS}}=0\text{V}$	-	-	25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=5\text{A}$	-	18	29	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=48\text{V}$	-	5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	10	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=30\text{V}$	-	10	-	ns
t_r	Rise Time	$I_{\text{D}}=1\text{A}$	-	6	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{\text{GS}}=10\text{V}$	-	32	-	ns
t_f	Fall Time	$R_D=30\Omega$	-	10	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1670	2670	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	160	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	117	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=1.7\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V
t_{rr}	Reverse Recovery Time ²	$I_{\text{S}}=5\text{A}, V_{\text{GS}}=0\text{V}$	-	34	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	48	-	nC



P-CH Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-60	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}, I_{\text{D}}=-1\text{mA}$	-	-0.04	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-4\text{A}$	-	-	72	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-3\text{A}$	-	-	88	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-4\text{A}$	-	6	-	S
I_{DSS}	Drain-Source Leakage Current ($T=25^\circ\text{C}$)	$V_{\text{DS}}=-60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	μA
	Drain-Source Leakage Current ($T=70^\circ\text{C}$)	$V_{\text{DS}}=-48\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-4\text{A}$	-	21	34	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-48\text{V}$	-	5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	9	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$V_{\text{DS}}=-30\text{V}$	-	12	-	ns
t_r	Rise Time	$I_{\text{D}}=-1\text{A}$	-	6	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{\text{GS}}=-10\text{V}$	-	82	-	ns
t_f	Fall Time	$R_D=30\Omega$	-	36	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1780	2850	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	157	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	130	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=-1.7\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time ²	$I_S=-4\text{A}, V_{\text{GS}}=0\text{V}$	-	43	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=-100\text{A}/\mu\text{s}$	-	87	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- 3.Surface mounted on 1 in² copper pad of FR4 board ; $135^\circ\text{C}/\text{W}$ when mounted on min. copper pad.



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N-Channel

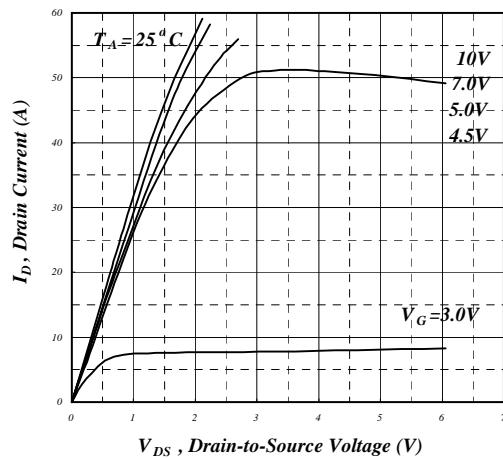


Fig 1. Typical Output Characteristics

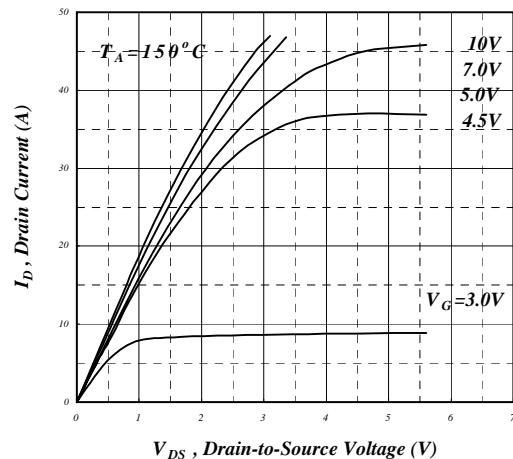


Fig 2. Typical Output Characteristics

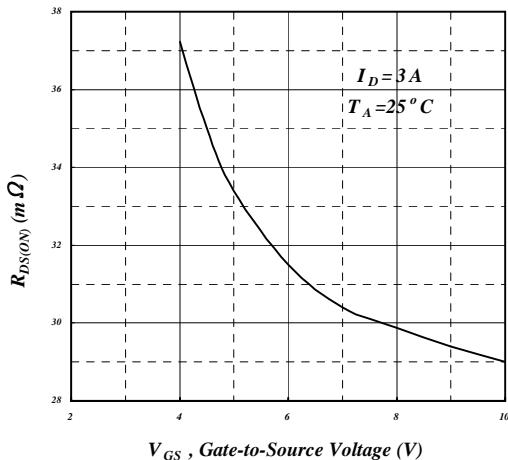


Fig 3. On-Resistance v.s. Gate Voltage

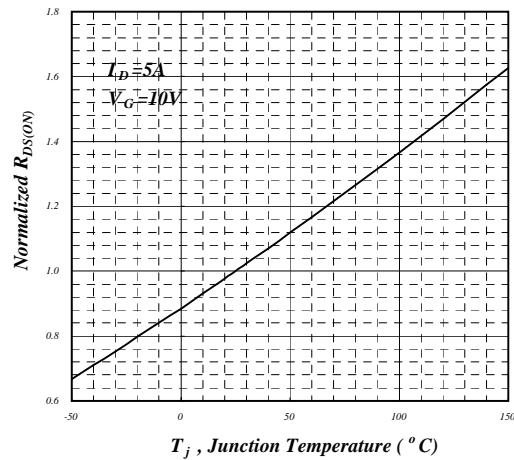


Fig 4. Normalized On-Resistance v.s. Junction Temperature

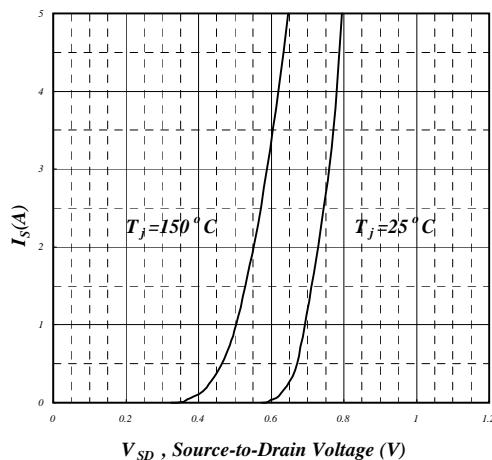


Fig 5. Forward Characteristic of Reverse Diode

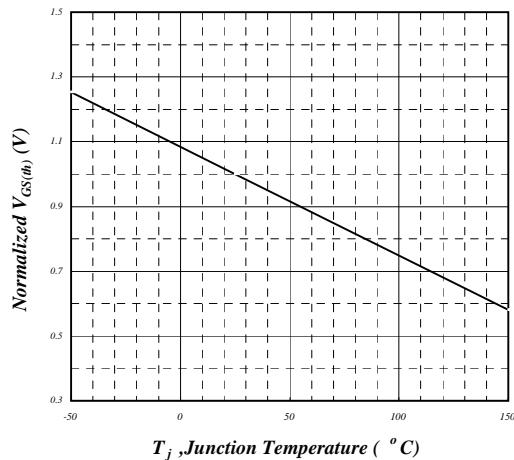
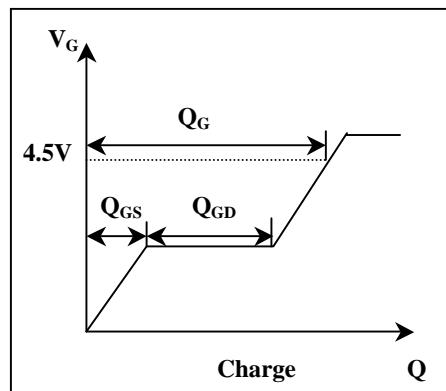
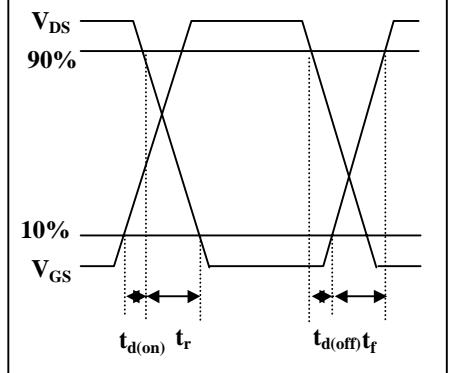
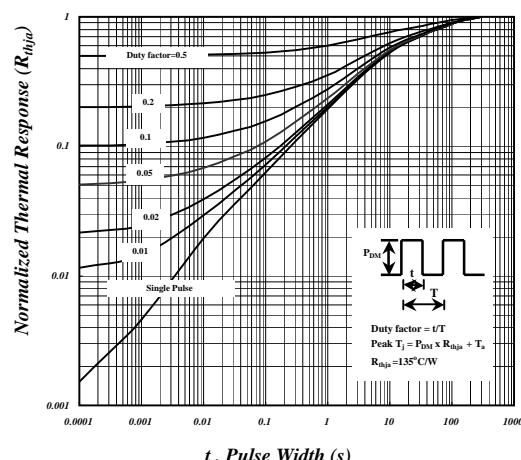
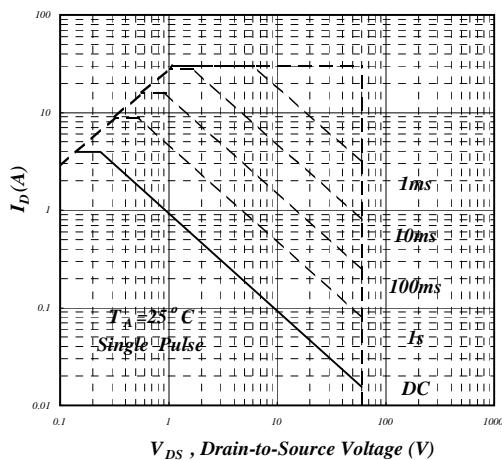
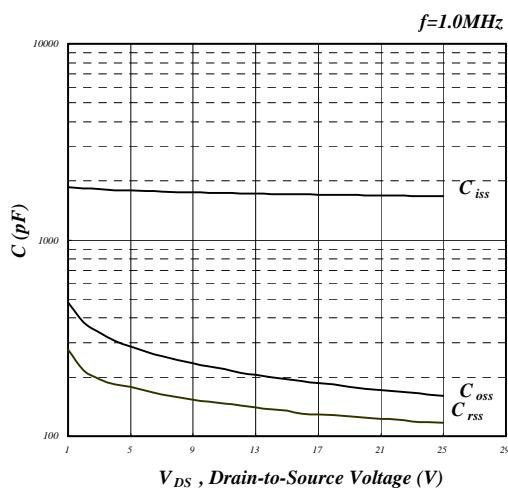
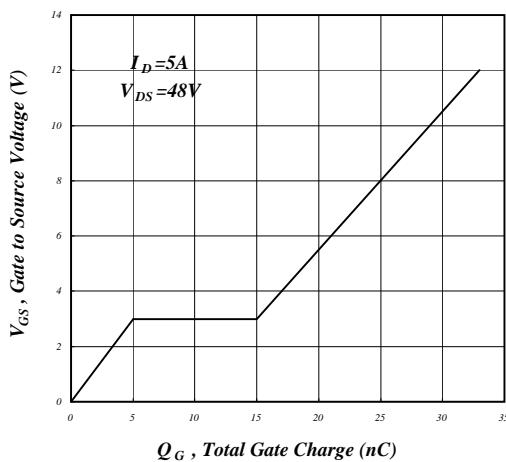


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



N-Channel





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P-Channel

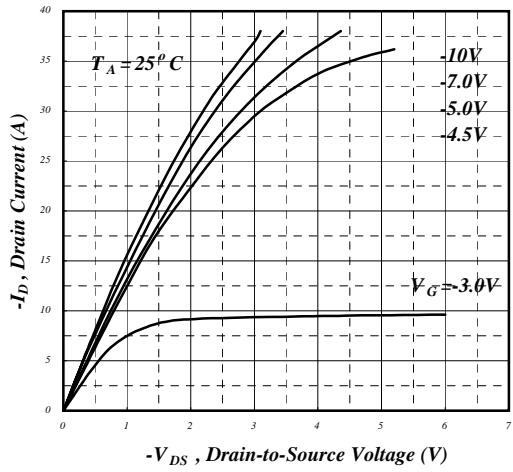


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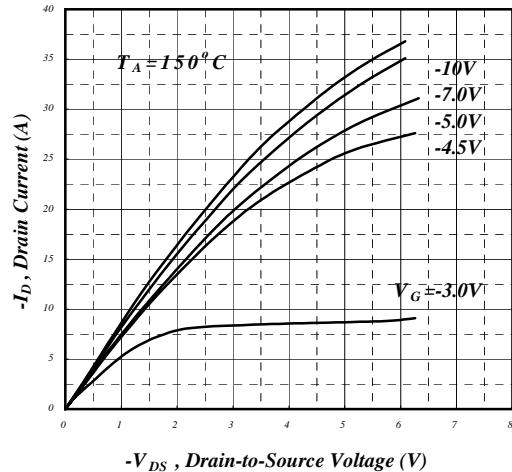


Fig 2. Typical Output Characteristics

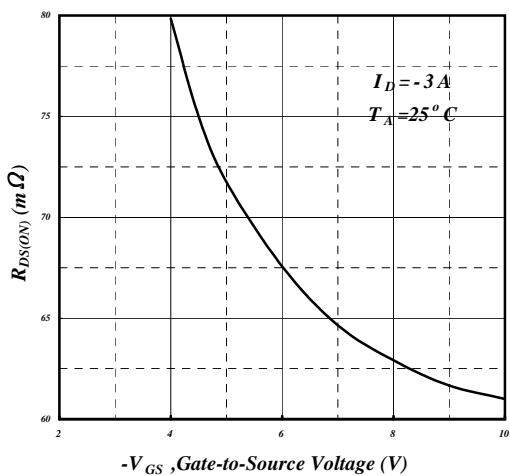


Fig 3. On-Resistance v.s. Gate Voltage

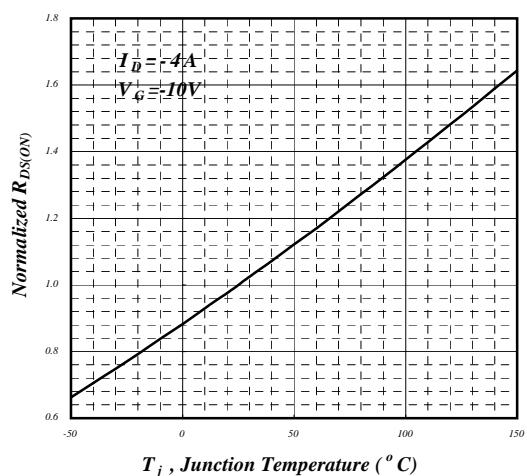


Fig 4. Normalized On-Resistance v.s. Junction Temperature

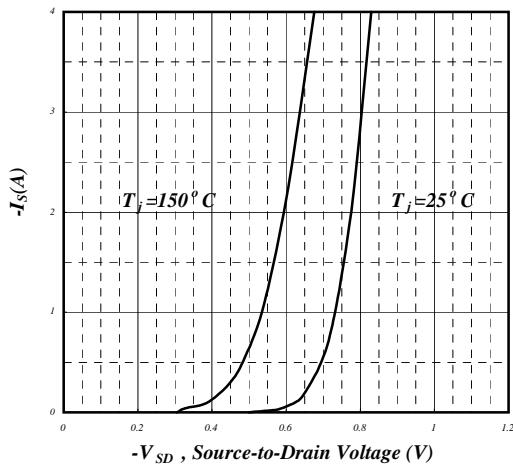


Fig 5. Forward Characteristic of Reverse Diode

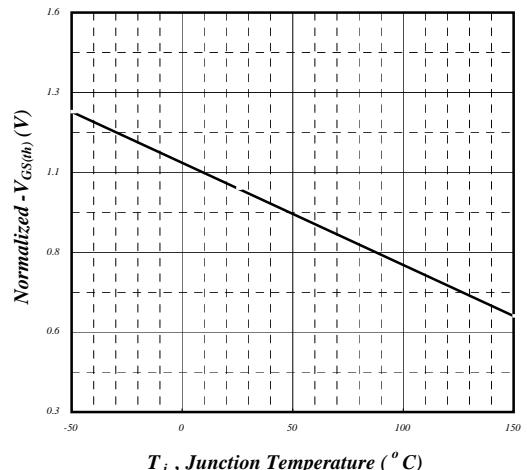


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

**P-Channel**